

18-bit bus-interface D-type flip-flop with reset and enable (3-State)

74ABT16823A
74ABTH16823A

FEATURES

- Two sets of high speed parallel registers with positive edge-triggered D-type flip-flops
- Ideal where high speed, light loading, or increased fan-in are required with MOS microprocessors
- Live insertion/extraction permitted
- Power-up 3-State
- 74ABT16823A incorporates bus-hold data inputs which eliminate the need for external pull-up resistors to hold unused inputs
- Power-up Reset
- Output capability: +64mA/-32mA
- Latch-up protection exceeds 500mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS $T_{amb} = 25^\circ\text{C}$; GND = 0V	TYPICAL	UNIT
t_{PLH} t_{PHL}	Propagation delay nCP to nQx	$C_L = 50\text{pF}$; $V_{CC} = 5\text{V}$	2.3 1.9	ns
C_{IN}	Input capacitance	$V_I = 0\text{V}$ or V_{CC}	4	pF
C_{OUT}	Output capacitance	$V_O = 0\text{V}$ or V_{CC} ; 3-State	6	pF
I_{CCZ}	Quiescent supply current	Outputs disabled; $V_{CC} = 5.5\text{V}$	500	μA
I_{CCL}		Outputs low; $V_{CC} = 5.5\text{V}$	9	mA

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
56-Pin Plastic SSOP Type III	-40°C to +85°C	74ABT16823A DL	BT16823A DL	SOT371-1
56-Pin Plastic TSSOP Type II	-40°C to +85°C	74ABT16823A DGG	BT16823A DGG	SOT364-1
56-Pin Plastic SSOP Type III	-40°C to +85°C	74ABTH16823A DL	BH16823A DL	SOT371-1
56-Pin Plastic TSSOP Type II	-40°C to +85°C	74ABTH16823A DGG	BH16823A DGG	SOT364-1

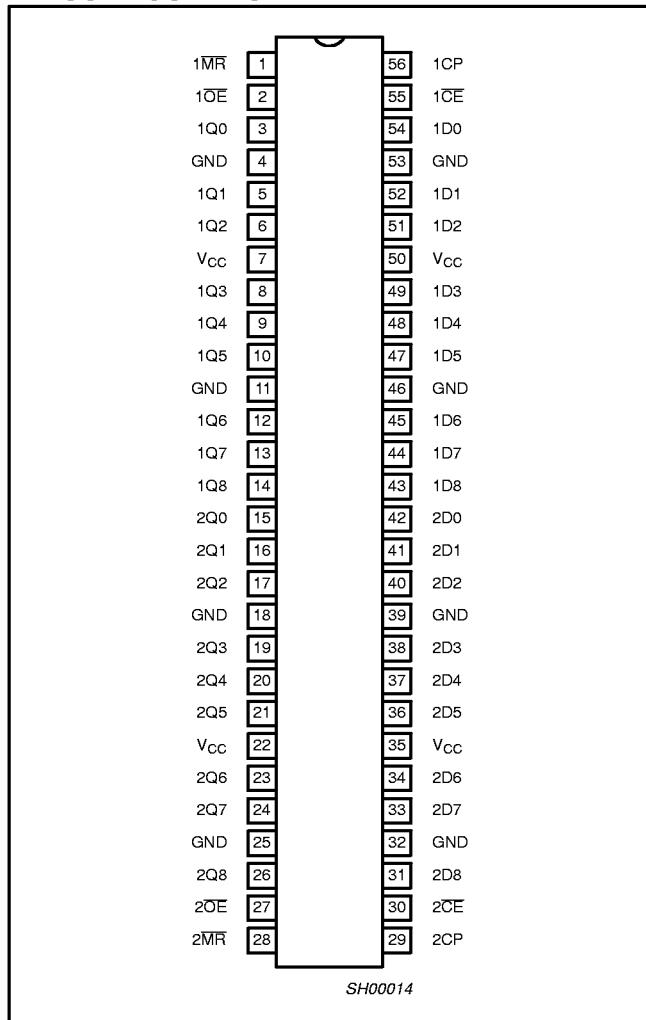
PIN DESCRIPTION

PIN NUMBER	SYMBOL	FUNCTION
2, 27	$1OE, 2OE$	Output enable input (active-Low)
54, 52, 51, 49, 48, 47, 45, 44, 43 42, 41, 40, 38, 37, 36, 34, 33, 31	1D0-1D8 2D0-2D8	Data inputs
3, 5, 6, 8, 9, 10, 12, 13, 14 15, 16, 17, 19, 20, 21, 23, 24, 26	1Q0-1Q8 2Q0-2Q8	Data outputs
56, 29	1CP, 2CP	Clock pulse input (active rising edge)
55, 30	1CE, 2CE	Clock enable input (active-Low)
1, 28	1MR, 2MR	Master reset input (active-Low)
4, 11, 18, 25, 32, 39, 46, 53	GND	Ground (0V)
7, 22, 35, 50	V_{CC}	Positive supply voltage

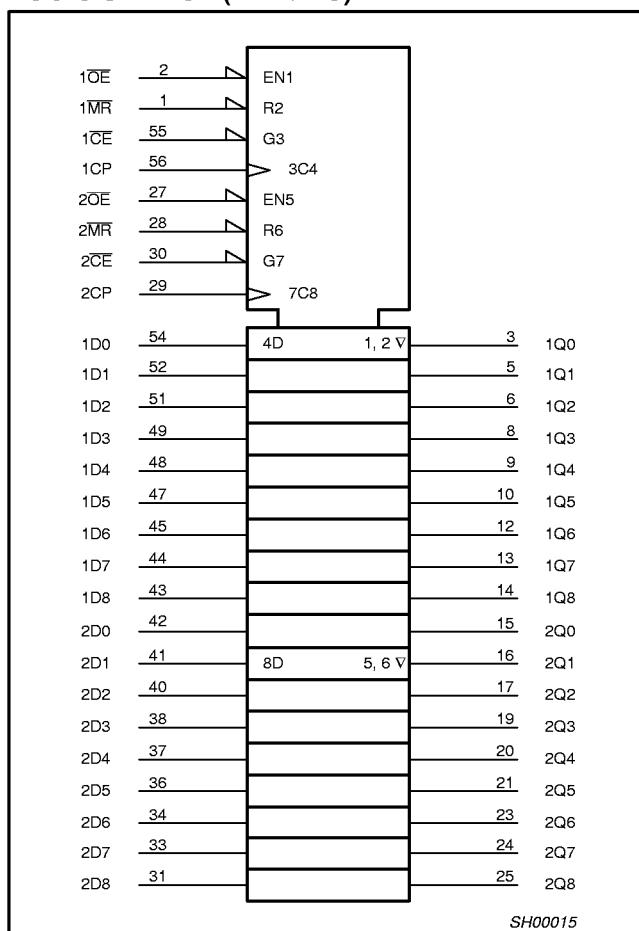
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PIN CONFIGURATION



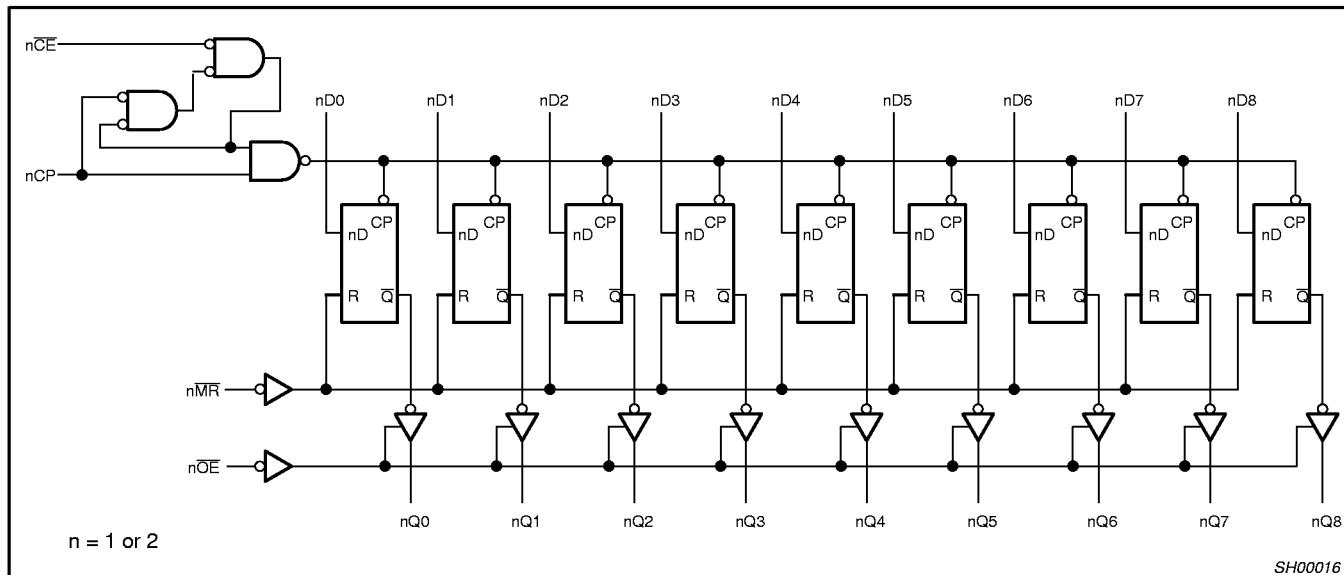
LOGIC SYMBOL (IEEE/IEC)



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LOGIC DIAGRAM



SH00016

FUNCTION TABLE

INPUTS					OUTPUTS	OPERATING MODE
nOE	nMR	nCE	nCP	nDx	nQ0 – nQ8	
L	L	X	X	X	L	Clear
L	H	L	↑	h	H	Load and read data
L	H	L	↑	I	L	
L	H	H	‡	X	NC	Hold
H	X	X	X	X	Z	High impedance

H = High voltage level

h = High voltage level one set-up time prior to the Low-to-High clock transition

L = Low voltage level

I = Low voltage level one set-up time prior to the Low-to-High clock transition

NC = No change

X = Don't care

Z = High impedance "off" state

↑ = Low to High clock transition

‡ = Not a Low-to-High clock transition

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ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V_{CC}	DC supply voltage		-0.5 to +7.0	V
I_{IK}	DC input diode current	$V_I < 0$	-18	mA
V_I	DC input voltage ³		-1.2 to +7.0	V
I_{OK}	DC output diode current	$V_O < 0$	-50	mA
V_{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V
I_{OUT}	DC output current	output in Low state	128	mA
		output in High state	-64	
T_{stg}	Storage temperature range		-65 to 150	°C

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS		UNIT
		MIN	MAX	
V_{CC}	DC supply voltage	4.5	5.5	V
V_I	Input voltage	0	V_{CC}	V
V_{IH}	High-level input voltage	2.0		V
V_{IL}	Low-level input voltage		0.8	V
I_{OH}	High-level output current		-32	mA
I_{OL}	Low-level output current		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V
T_{amb}	Operating free-air temperature range	-40	+85	°C

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DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS					UNIT	
			$T_{amb} = +25^{\circ}\text{C}$			$T_{amb} = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$			
			MIN	TYP	MAX	MIN	MAX		
V_{IK}	Input clamp voltage	$V_{CC} = 4.5\text{V}; I_{IK} = -18\text{mA}$		-0.9	-1.2		-1.2	V	
V_{OH}	High-level output voltage	$V_{CC} = 4.5\text{V}; I_{OH} = -3\text{mA}; V_I = V_{IL} \text{ or } V_{IH}$	2.5	2.9		2.5		V	
		$V_{CC} = 5.0\text{V}; I_{OH} = -3\text{mA}; V_I = V_{IL} \text{ or } V_{IH}$	3.0	3.4		3.0		V	
		$V_{CC} = 4.5\text{V}; I_{OH} = -32\text{mA}; V_I = V_{IL} \text{ or } V_{IH}$	2.0	2.4		2.0		V	
V_{OL}	Low-level output voltage	$V_{CC} = 4.5\text{V}; I_{OL} = 64\text{mA}; V_I = V_{IL} \text{ or } V_{IH}$		0.42	0.55		0.55	V	
V_{RST}	Power-up output low voltage ³	$V_{CC} = 5.5\text{V}; I_{OL} = 1\text{mA}; V_I = \text{GND or } V_{CC}$		0.13	0.55		0.55	V	
I_I	Input leakage current	$V_{CC} = 5.5\text{V}; V_I = V_{CC} \text{ or GND}$		± 0.01	± 1		± 1	μA	
I_I	Input leakage current 74ABTH16823A	$V_{CC} = 5.5\text{V}; V_I = V_{CC} \text{ or GND}$	Control pins	± 0.01	± 1		± 1	μA	
		$V_{CC} = 5.5\text{V}; V_I = V_{CC}$	Data pins	0.01	1		1	μA	
		$V_{CC} = 5.5\text{V}; V_I = 0$		-2	-3		-5	μA	
I_{HOLD}	Bus Hold current inputs ⁵ 74ABTH16823A	$V_{CC} = 4.5\text{V}; V_I = 0.8\text{V}$	35			35		μA	
		$V_{CC} = 4.5\text{V}; V_I = 2.0\text{V}$	-75			-75			
		$V_{CC} = 5.5\text{V}; V_I = 0 \text{ to } 5.5\text{V}$	± 800						
I_{OFF}	Power-off leakage current	$V_{CC} = 0.0\text{V}; V_O \text{ or } V_I \leq 4.5\text{V}$		± 5.0	± 100		± 100	μA	
$I_{PU/PD}$	Power-up/down 3-State output current ⁴	$V_{CC} = 2.1\text{V}; V_O = 0.5\text{V}; V_I = \text{GND or } V_{CC}; V_{OE} = \text{Don't care}$		± 5.0	± 50		± 50	μA	
I_{OZH}	3-State output High current	$V_{CC} = 5.5\text{V}; V_O = 2.7\text{V}; V_I = V_{IL} \text{ or } V_{IH}$		1.0	10		10	μA	
I_{OZL}	3-State output Low current	$V_{CC} = 5.5\text{V}; V_O = 0.5\text{V}; V_I = V_{IL} \text{ or } V_{IH}$		-1.0	-10		-10	μA	
I_{CEX}	Output High leakage current	$V_{CC} = 5.5\text{V}; V_O = 5.5\text{V}; V_I = \text{GND or } V_{CC}$		50	50		50	μA	
I_O	Output current ¹	$V_{CC} = 5.5\text{V}; V_O = 2.5\text{V}$	-50	-80	-180	-50	-180	mA	
I_{CCH}	Quiescent supply current	$V_{CC} = 5.5\text{V}; \text{Outputs High, } V_I = \text{GND or } V_{CC}$		0.5	1		1	mA	
I_{CCL}		$V_{CC} = 5.5\text{V}; \text{Outputs Low, } V_I = \text{GND or } V_{CC}$		9.0	19		19	mA	
I_{CCZ}		$V_{CC} = 5.5\text{V}; \text{Outputs 3-State; } V_I = \text{GND or } V_{CC}$		0.5	1		1	mA	
ΔI_{CC}	Additional supply current per input pin ²	$V_{CC} = 5.5\text{V}; \text{one input at } 3.4\text{V, other inputs at } V_{CC} \text{ or GND}$		0.2	1		1	mA	

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
2. This is the increase in supply current for each input at 3.4V.
3. For valid test results, data must not be loaded into the flip-flops (or latches) after applying the power.
4. This parameter is valid for any V_{CC} between 0V and 2.1V with a transition time of up to 10msec. From $V_{CC} = 2.1\text{V}$ to $V_{CC} = 5\text{V} \pm 10\%$ a transition time of up to 100 μsec is permitted.
5. This is the bus hold overdrive current required to force the input to the opposite logic state.

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AC CHARACTERISTICS

GND = 0V, $t_R = t_F = 2.5\text{ns}$, $C_L = 50\text{pF}$, $R_L = 500\Omega$

SYMBOL	PARAMETER	WAVEFORM	LIMITS					UNIT	
			$T_{amb} = +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$			$T_{amb} = -40^\circ\text{C}$ $\text{to } +85^\circ\text{C}$ $V_{CC} = +5.0\text{V} \pm 0.5\text{V}$			
			MIN	TYP	MAX	MIN	MAX		
f_{MAX}	Maximum clock frequency	1	140	190		140		MHz	
t_{PLH} t_{PHL}	Propagation delay nCP to nQx	1	1.4 1.2	2.3 1.9	3.2 2.6	1.4 1.2	3.7 2.9	ns	
t_{PHL}	Propagation delay nMR to nQx	2	2.0	3.3	4.3	2.0	5.0	ns	
t_{PZH} t_{PZL}	Output enable time to High and Low level	4 5	1.3 1.2	2.4 2.1	3.2 2.9	1.3 1.2	3.9 3.4	ns	
t_{PHZ} t_{PLZ}	Output disable time from High and Low level	4 5	1.7 1.6	2.9 2.3	4.0 3.2	1.7 1.6	4.7 3.4	ns	

AC SETUP REQUIREMENTS

GND = 0V, $t_R = t_F = 2.5\text{ns}$, $C_L = 50\text{pF}$, $R_L = 500\Omega$

SYMBOL	PARAMETER	WAVEFORM	LIMITS			UNIT
			$T_{amb} = +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$		$T_{amb} = -40^\circ\text{C}$ $\text{to } +85^\circ\text{C}$ $V_{CC} = +5.0\text{V} \pm 0.5\text{V}$	
			MIN	TYP	MIN	
$t_s(H)$ $t_s(L)$	Setup time, High or Low nDx to nCP	3	2.0 1.5	1.3 0.9	2.0 1.5	ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low nDx to nCP	3	1.5 1.5	-0.9 -1.2	1.5 1.5	ns
$t_w(H)$ $t_w(L)$	nCP pulse width High or Low	1	3.3 3.3	1.7 1.7	3.3 3.3	ns
$t_s(H)$ $t_s(L)$	Setup time, High or Low nCE to nCP	3	1.5 2.0	0.9 0.9	1.5 2.0	ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low nCE to nCP	3	1.5 1.5	-0.8 -0.9	1.5 1.5	ns
$t_w(L)$	nMR pulse width, Low	2	3.0	1.7	3.0	ns
t_{rec}	Recovery time nMR to nCP	2	2.5	1.0	2.5	ns

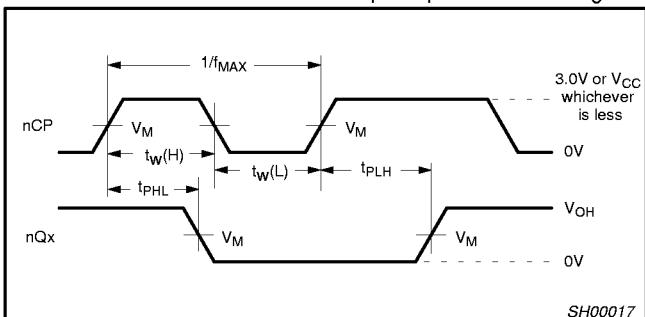
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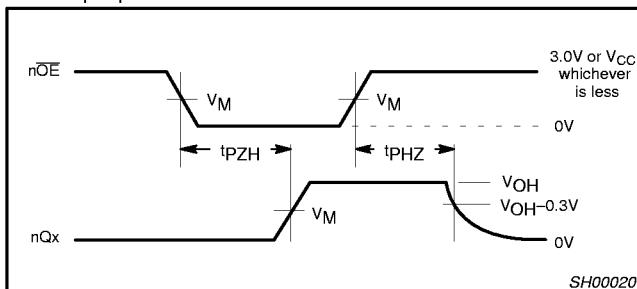
AC WAVEFORMS

For all waveforms, $V_M = 1.5V$.

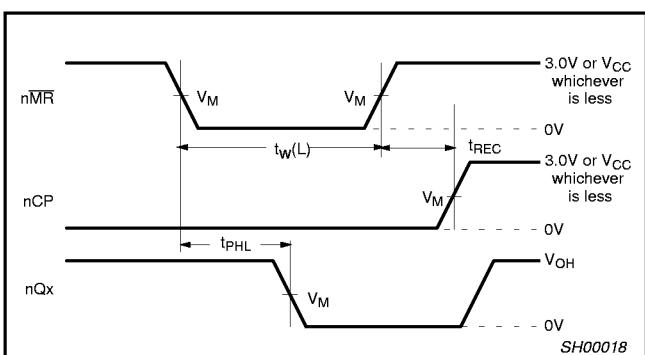
The shaded areas indicate when the input is permitted to change for predictable output performance.



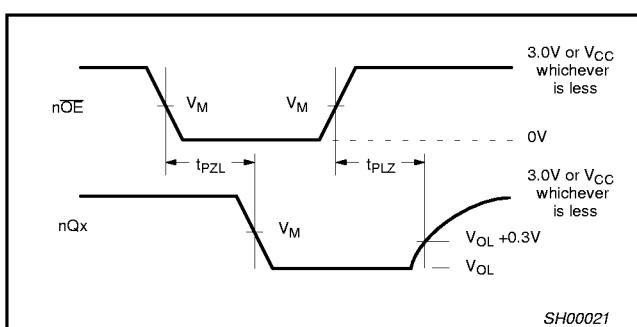
**Waveform 1. Propagation Delay, Clock Input to Output,
Clock Pulse Width, and Maximum Clock Frequency**



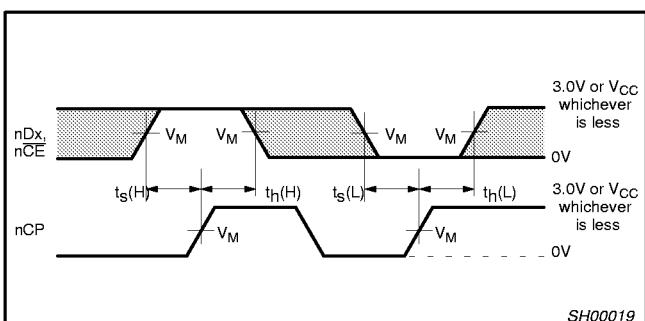
**Waveform 4. 3-State Output Enable Time to High Level
and Output Disable Time from High Level**



**Waveform 2. Master Reset Pulse Width, Master Reset to
Output Delay and Master Reset to Clock Recovery Time**



**Waveform 5. 3-State Output Enable Time to Low Level
and Output Disable Time from Low Level**

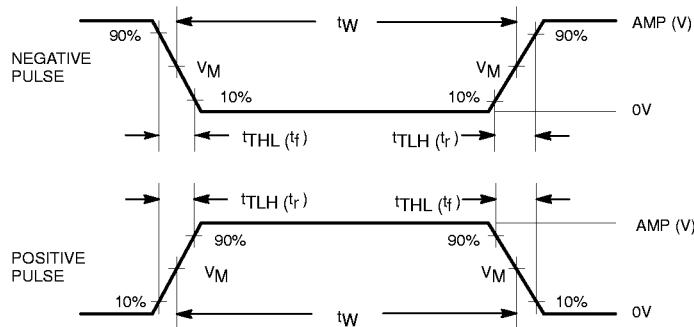
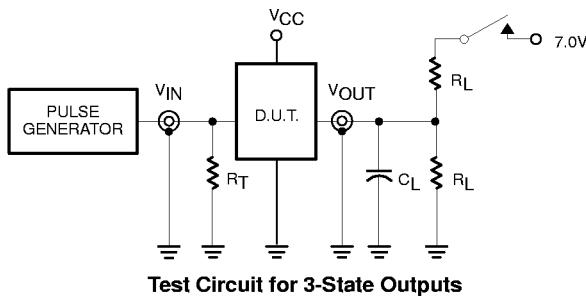


Waveform 3. Data Setup and Hold Times

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74ABT16823A
74ABTH16823A

TEST CIRCUIT AND WAVEFORM



SWITCH POSITION

TEST	SWITCH
t_{PLZ}	closed
t_{PZL}	closed
All other	open

DEFINITIONS:

R_L = Load resistor; see AC CHARACTERISTICS for value.

C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.

R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_w	t_R	t_F
74ABT16	3.0V	1MHz	500ns	2.5ns	2.5ns

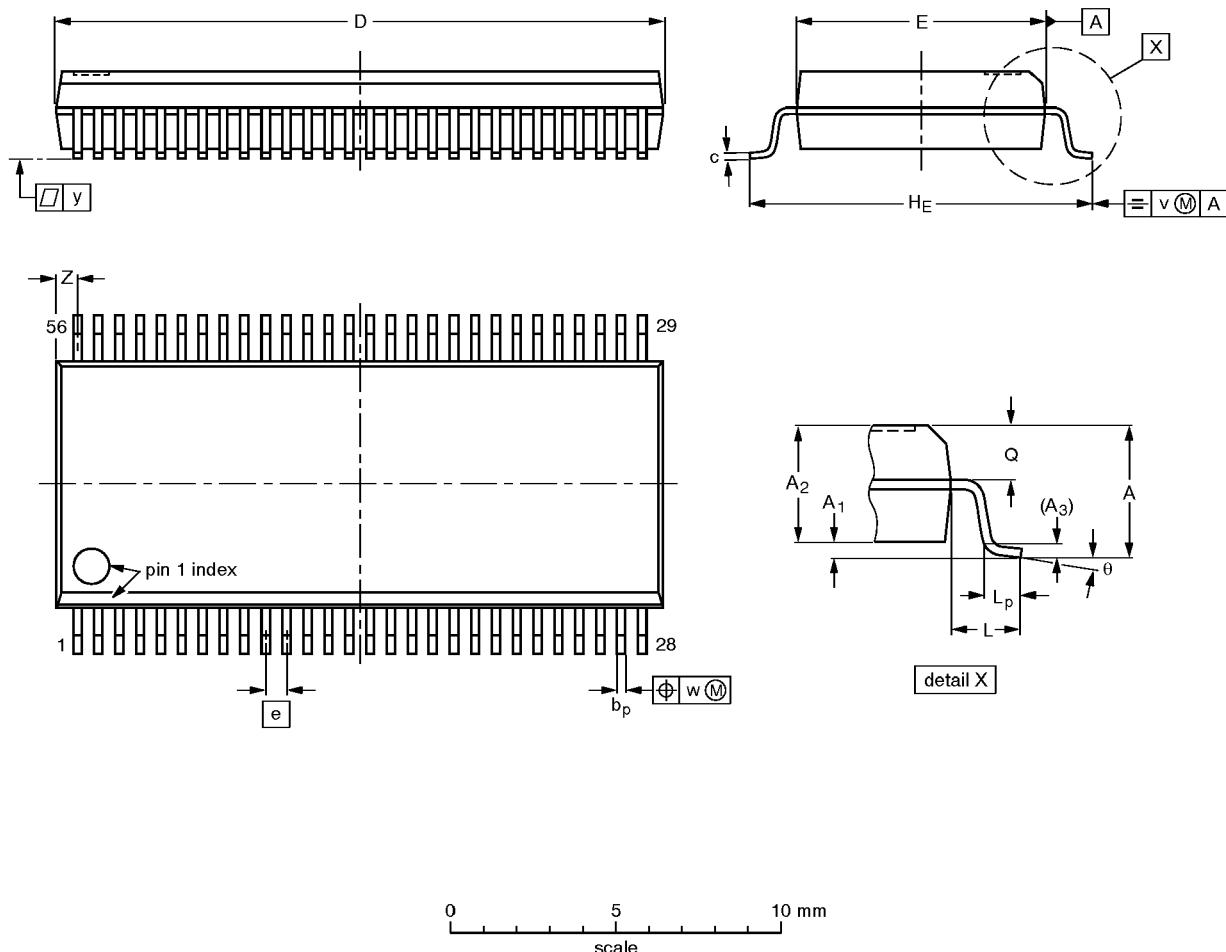
SH00022

**18-bit bus-interface D-type flip-flop
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74ABTH16823A**

SSOP56: plastic shrink small outline package; 56 leads; body width 7.5 mm

SOT371-1



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A ₁	A ₂	A ₃	b _p	c	D ⁽¹⁾	E ⁽¹⁾	e	H _E	L	L _p	Q	v	w	y	z ⁽¹⁾	θ
mm	2.8 0.2	0.4 0.2	2.35 2.20	0.25	0.3 0.2	0.22 0.13	18.55 18.30	7.6 7.4	0.635	10.4 10.1	1.4	1.0 0.6	1.2 1.0	0.25	0.18	0.1	0.85 0.40	8° 0°

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT371-1		MO-118AB				93-11-02 95-02-04

18-bit bus-interface D-type flip-flop
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TSSOP56: plastic thin shrink small outline package; 56 leads; body width 6.1mm

SOT364-1

